

S1: AR<0.1% @ 355 nm, AOI 0 deg.
S2: AR<0.1% @ 355 nm, AOI 0 deg.

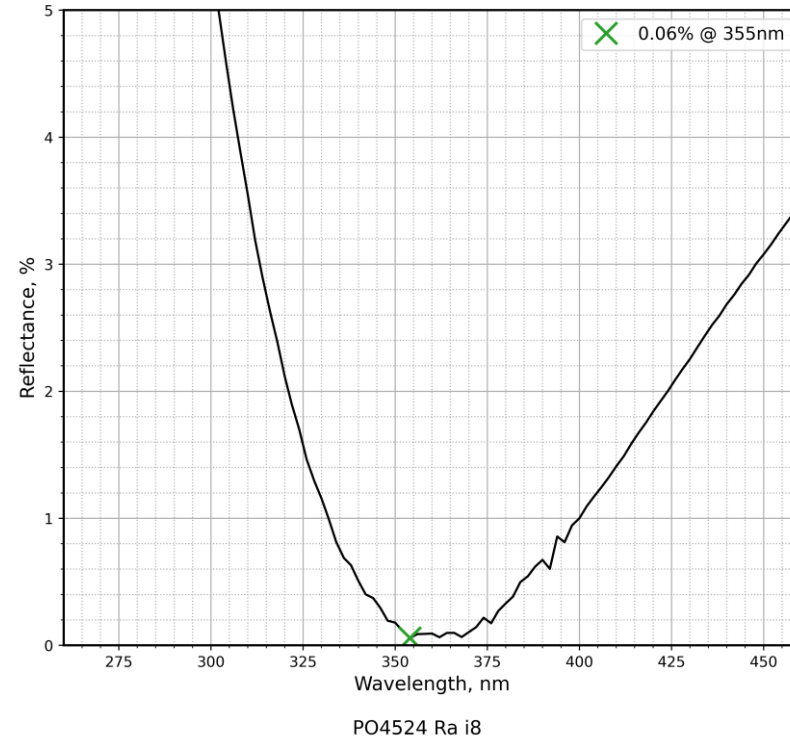
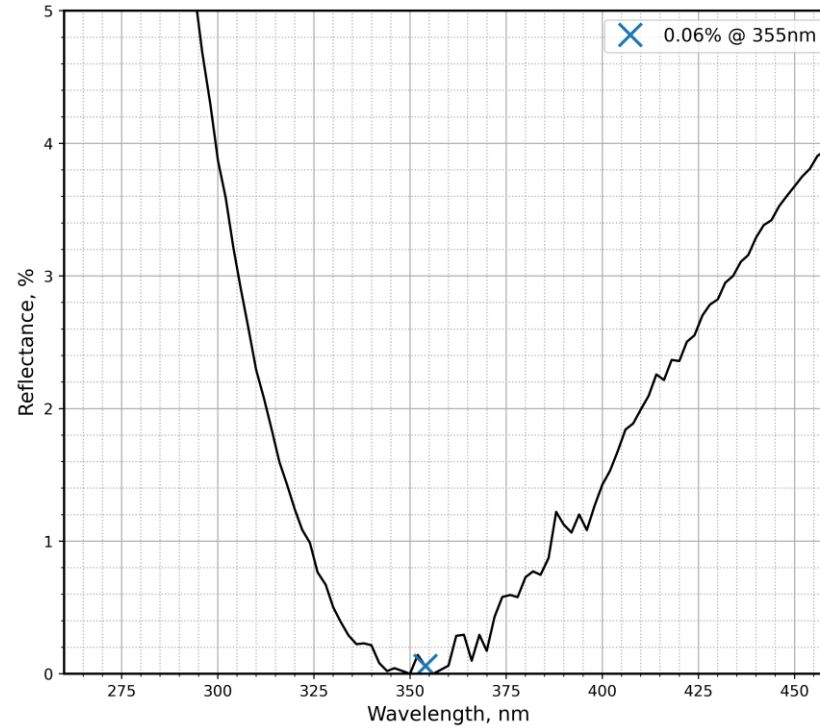


Fig. 1.

SIDE MEASURED: S1 only (grinded witness sample)

COMMENTS:

S1: AR<0.1% @ 355 nm, AOI 0 deg.
S2: AR<0.1% @ 355 nm, AOI 0 deg.



PO4524 Ra i8

Fig. 2.

SIDE MEASURED: S2 only (grinded witness sample)

COMMENTS: Margin of measurement error: +/-0.25%